Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	_
10/801,008	BENJAMIN ET AL.	
Examiner	Art Unit	_
Hieu Nguyen	2817	

	SEARCHED			
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Class	Subclass	Date	Examiner	
330	149	7/8/2005	HN	
330	52	7/11/2005	HN	
330	151	7/12/2005	HN	
330	52	7/12/2005	HN	
330	149	7/12/2005	HN	
330	52	7/14/2005	HN	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH (INCLUDING SEAF)
	\ DATE	EXMR
MOTTOLA STEVEN J	7/11/2005	HN
NGUYEN KHANH V	7/11/2005	HN
MOTTOLA STEVEN J	7/13/2005	HN
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